



SLOVENSKI STANDARD

SIST EN ISO 4287:2000

01-december-2000

Specifikacija geometrijskih veličin izdelka - Tekstura površine: profilna metoda - Poimenovanja, definicije in parametri tekture površine

Geometrical product specifications (GPS) - Surface texture: Profile method - Terms, definitions and surface texture parameters (ISO 4287:1997)

Geometrische Produktspezifikationen (GPS) - Oberflächenbeschaffenheit: Tastschnitverfahren - Benennungen, Definitionen und Kenngrößen der Oberflächenbeschaffenheit (ISO 4287:1997)

**HEN STANDARD PREVIEW
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Spécification géométrique des produits (GPS) - Etat de surface: Méthode du profil - Termes, définitions et paramètres d'état de surface (ISO 4287:1997)
<https://standards.iteh.ai/catalog/standards/sist/standards/sist-en-iso-4287-2000-946305ae3b4f/sist-en-iso-4287-2000>

Ta slovenski standard je istoveten z: **EN ISO 4287:1998**

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17.040.20	Lastnosti površin	Properties of surfaces

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN ISO 4287

August 1998

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Descriptors: see ISO document

English version

**Geometrical product specifications (GPS) - Surface texture:
 Profile method - Terms, definitions and surface texture
 parameters (ISO 4287:1997)**

Spécification géométrique des produits (GPS) - Etat de surface: Méthode du profil - Termes, définitions et paramètres d'état de surface (ISO 4287:1997)

Geometrische Produktspezifikationen (GPS) - Oberflächenbeschaffenheit: Tastschnittverfahren - Benennungen, Definitionen und Kenngrößen der Oberflächenbeschaffenheit (ISO 4287:1997)

This European Standard was approved by CEN on 26 January 1998.

CEN members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration. Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CEN member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CEN member into its own language and notified to the Central Secretariat has the same status as the official versions.

[SIST EN ISO 4287:2000](http://standards.cenelec.eu/standard.aspx?ref=946305ae5b4/sist-en-iso-4287-2000)

CEN members are the national standards bodies of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.



EUROPEAN COMMITTEE FOR STANDARDIZATION
 COMITÉ EUROPÉEN DE NORMALISATION
 EUROPÄISCHES KOMITEE FÜR NORMUNG

Central Secretariat: rue de Stassart, 36 B-1050 Brussels

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EN ISO 4287:1998

Foreword

The text of the International Standard from Technical Committee ISO/TC 213 "Dimensional and geometrical product specifications and verification" of the International Organization for Standardization (ISO) has been taken over as an European Standard by Technical Committee CEN/TC 290 "Dimensional and geometrical product specification and verification", the secretariat of which is held by DIN.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by February 1999, and conflicting national standards shall be withdrawn at the latest by February 1999.

According to the CEN/CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard: Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and the United Kingdom.

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Endorsement notice

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The text of the International Standard ISO 4287:1997 has been approved by CEN as a European Standard without any modification.

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NOTE: Normative references to International Standards are listed in annex ZA (normative).

<https://standards.iteh.ai/codes/technical/jstd-013420-70-9-15-5-06b>

946305ae3b4f/sist-en-iso-4287-2000

Annex ZA (normative)**Normative references to international publications
with their relevant European publications**

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN</u>	<u>Year</u>
ISO 4288	1996	Geometrical product specifications (GPS) - Surface texture: Profile method - Rules and procedures for the assessment of surface texture	EN ISO 4288	1997
ISO 11562	1996	Geometrical product specifications (GPS) - Surface texture: Profile method - Metrological characteristics of phase correct filter	EN ISO 11562	1997

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INTERNATIONAL
STANDARD

ISO
4287

NORME
INTERNATIONALE

First edition
Première édition
1997-04-01

**Geometrical Product Specifications
(GPS) — Surface texture: Profile method —
Terms, definitions and surface texture
parameters**

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(standards.iteh.ai)

**Spécification géométrique des produits
(GPS) — Etat de surface: Méthode
du profil — Termes, définitions et
paramètres d'état de surface**

<https://standards.iteh.ai/catalog/taf/td/sisid/01/0100/00/45e599946305ae2b4f/sist-en-iso-4287-2000>



Reference number
Numéro de référence
ISO 4287:1997(E/F)

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

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International Standard ISO 4287 was prepared by Technical Committee ISO/TC 57, *Metrology and properties of surfaces*, and has been based on studies carried out by the Joint Harmonization Group of ISO/TC 3, *Limits and fits*, ISO/TC 10, *Technical drawings, product definition and related documentation*, SC 5, *Dimensioning and tolerancing*, and ISO/TC 67, *Metrology and properties of surfaces*. <https://standards.tech.iteh.afr/SIST-EN-ISO-4287-2000>

This first edition of ISO 4287 cancels and replaces ISO 4287-1:1984. This revision of ISO 4287-1:1984; is a major rewrite and reorganization that, together with ISO 11562 and ISO 3274, additionally defines the waviness profile, the primary profile and their parameters in a consistent manner.

Annex A forms an integral part of this International Standard. Annexes B, C, D and E are for information only.

Avant-propos

L'ISO (Organisation internationale de normalisation) est une fédération mondiale d'organismes nationaux de normalisation (comités membres de l'ISO). L'élaboration des Normes internationales est en général confiée aux comités techniques de l'ISO. Chaque comité membre intéressé par une étude a le droit de faire partie du comité technique créé à cet effet. Les organisations internationales, gouvernementales et non gouvernementales, en liaison avec l'ISO participent également aux travaux. L'ISO collabore étroitement avec la Commission électrotechnique internationale (CEI) en ce qui concerne la normalisation électrotechnique.

Les projets de Normes internationales adoptés par les comités techniques sont soumis aux comités membres pour vote. Leur publication comme Normes internationales requiert l'approbation de 75 % au moins des comités membres votants.

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(standards.techinternational.com/iso/iso-4287-2000)
La Norme internationale ISO 4287 a été élaborée par le comité technique ISO/TC 57, *Métrie et propriétés des surfaces*, sous-comité SC 1, *Paramètres géométriques — Instruments et procédures pour la mesure de la rugosité et de l'ondulation des surfaces*, et tient compte des études menées par le groupe d'harmonisation joint entre l'ISO/TC 3, *Ajustements*, l'ISO/TC 10, *Dessins techniques, définitions de produits et documentation y relative*, sous-comité SC 5, *Cotation et tolérancement* et l'ISO/TC 57, *Métrie et propriétés des surfaces*.

Cette première édition de l'ISO 4287 annule et remplace l'ISO 4287-1:1984. Cette révision constitue une réorganisation et une réécriture importantes de l'ISO 4287-1:1984; avec l'ISO 11562 et l'ISO 3274, elle ajoute, de façon cohérente, les définitions du profil d'ondulation, du profil primaire ainsi que de leurs paramètres.

L'annexe A fait partie intégrante de la présente Norme internationale. Les annexes B, C, D et E sont données uniquement à titre d'information.

Introduction

This International Standard is a Geometrical Product Specification (GPS) standard and is to be regarded as a General GPS standard (see ISO/TR 14638). It influences chain link 2 of the chains of standards on surface texture.

For more detailed information on the relationship of this International Standard to other standards and the GPS matrix model, see annex E.

Historically, the roughness profile and its parameters have been the only parts of surface texture characterization that have been well defined.

A default relationship between λ_c and λ_f is under consideration.

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